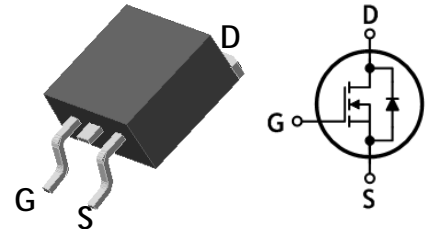


SWITCHING REGULATOR APPLICATION

Features

- High voltage: $BV_{DSS}=250V$ (Min.)
- Low gate charge: $Q_g=14.5nC$ (Typ.)
- Low drain-source On resistance: $R_{DS(on)}=0.43\Omega$ (Max.)
- 100% avalanche tested
- RoHS compliant device

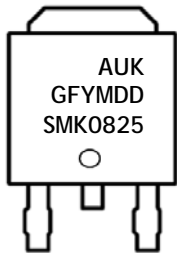


D2-PAK

Ordering Information

Part Number	Marking	Package
SMK0825D2	SMK0825	D2-PAK

Marking Information



Column 1: Manufacturer
 Column 2: Production Information
 e.g.) GFYMDD
 - . G: Option Code (H: Halogen Free)
 - . F: Factory Management Code
 - . YMDD: Date Code (Year, Month, Date)
 Column 3: Device Code

Absolute maximum ratings ($T_c=25^\circ C$ unless otherwise noted)

Characteristic	Symbol	Rating	Unit	
Drain-source voltage	V_{DSS}	250	V	
Repetitive Avalanche Voltage ^(Note 1, 2)	$V_{DS(Avalanche)}$	300	V	
Gate-source voltage	V_{GSS}	± 30	V	
Drain current (DC) *	I_D	$T_c=25^\circ C$	8	A
		$T_c=100^\circ C$	5.2	A
Drain current (Pulsed) *	I_{DM}	32	A	
Single pulsed avalanche energy ^(Note 2)	E_{AS}	356	mJ	
Repetitive avalanche current ^(Note 1)	I_{AR}	8	A	
Repetitive avalanche energy ^(Note 1)	E_{AR}	7.4	mJ	
Power dissipation	P_D	130	W	
Junction temperature	T_J	150	$^\circ C$	
Storage temperature range	T_{stg}	-55~150	$^\circ C$	

* Limited only maximum junction temperature

Thermal Characteristics

Characteristic	Symbol	Rating	Unit
Thermal resistance, junction to case	$R_{th(j-c)}$	Max. 0.96	°C/W
Thermal resistance, junction to ambient	$R_{th(j-a)}$	Max. 62.5	

Electrical Characteristics ($T_C=25^\circ\text{C}$ unless otherwise noted)

Characteristic	Symbol	Test Condition	Min.	Typ.	Max.	Unit
Drain-source breakdown voltage	BV_{DSS}	$I_D=250\mu\text{A}$, $V_{GS}=0$	250	-	-	V
Gate threshold voltage	$V_{GS(th)}$	$I_D=250\mu\text{A}$, $V_{DS}=V_{GS}$	2	-	4	V
Drain-source cut-off current	I_{DSS}	$V_{DS}=250\text{V}$, $V_{GS}=0\text{V}$	-	-	1	μA
Gate leakage current	I_{GSS}	$V_{DS}=0\text{V}$, $V_{GS}=\pm 30\text{V}$	-	-	± 100	nA
Drain-source on-resistance	$R_{DS(on)}$	$V_{GS}=10\text{V}$, $I_D=4\text{A}$	-	0.35	0.43	Ω
Internal gate resistance	R_G	$f=1\text{MHz}$, $V_{DS}=0\text{V}$	-	4	10	Ω
Forward transfer conductance (Note 3)	g_{fs}	$V_{DS}=10\text{V}$, $I_D=4\text{A}$	-	7	-	S
Input capacitance	C_{iss}	$V_{DS}=25\text{V}$, $V_{GS}=0\text{V}$, $f=1\text{MHz}$	-	619	773	pF
Output capacitance	C_{oss}		-	141	176	
Reverse transfer capacitance	C_{rss}		-	33	41	
Turn-on delay time (Note 3,4)	$t_{d(on)}$	$V_{DD}=125\text{V}$, $I_D=8\text{A}$ $R_G=25\Omega$	11	15	35	ns
Rise time (Note 3,4)	t_r		32	85	115	
Turn-off delay time (Note 3,4)	$t_{d(off)}$		62	90	135	
Fall time (Note 3,4)	t_f		41	65	98	
Total gate charge (Note 3,4)	Q_g	$V_{DS}=200\text{V}$, $V_{GS}=10\text{V}$ $I_D=8\text{A}$	-	14.5	18.2	nC
Gate-source charge (Note 3,4)	Q_{gs}		-	4	-	
Gate-drain charge (Note 3,4)	Q_{gd}		-	4.5	-	

Source-Drain Diode Ratings and Characteristics ($T_C=25^\circ\text{C}$ unless otherwise noted)

Characteristic	Symbol	Test Condition	Min.	Typ.	Max.	Unit
Source current (DC)	I_S	Integral reverse diode in the MOSFET	-	-	8	A
Source current (Pulsed)	I_{SM}		-	-	32	A
Forward voltage	V_{SD}	$V_{GS}=0\text{V}$, $I_S=8\text{A}$	-	-	1.4	V
Reverse recovery time (Note 3,4)	t_{rr}	$I_S=8\text{A}$, $V_{GS}=0\text{V}$ $di_F/dt=100\text{A}/\mu\text{s}$	-	178	-	ns
Reverse recovery charge (Note 3,4)	Q_{rr}		-	1.16	-	μC

Note:

1. Repeated rating: Pulse width limited by maximum junction temperature
2. $L=8.9\text{mH}$, $I_{AS}=8\text{A}$, $V_{DD}=50\text{V}$, $R_G=25\Omega$, Starting $T_J=25^\circ\text{C}$
3. Pulse test: Pulse width $\leq 300\mu\text{s}$, Duty cycle $\leq 2\%$
4. Essentially independent of operating temperature typical characteristics

Electrical Characteristic Curves

Fig. 1 $I_D - V_{DS}$

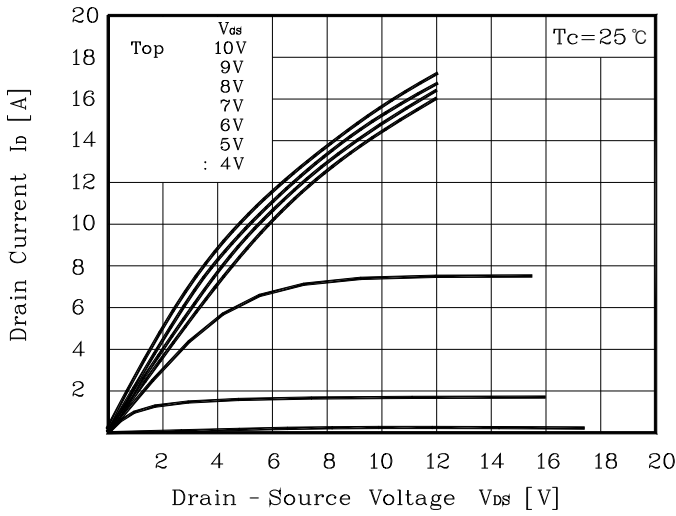


Fig. 2 $I_D - V_{GS}$

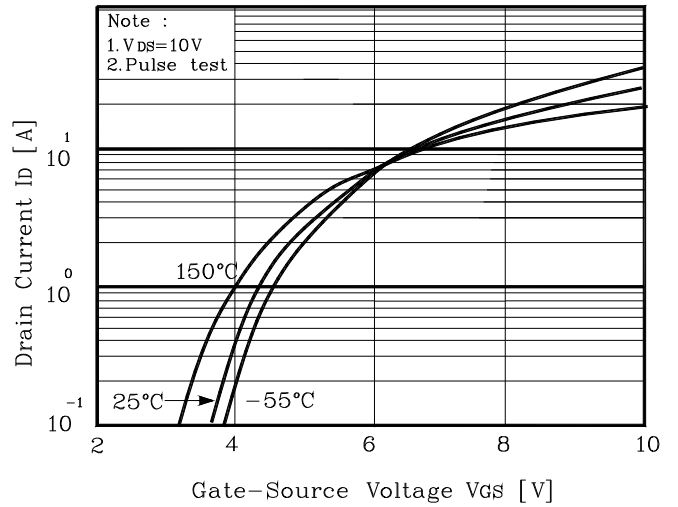


Fig. 3 $R_{DS(ON)} - I_D$

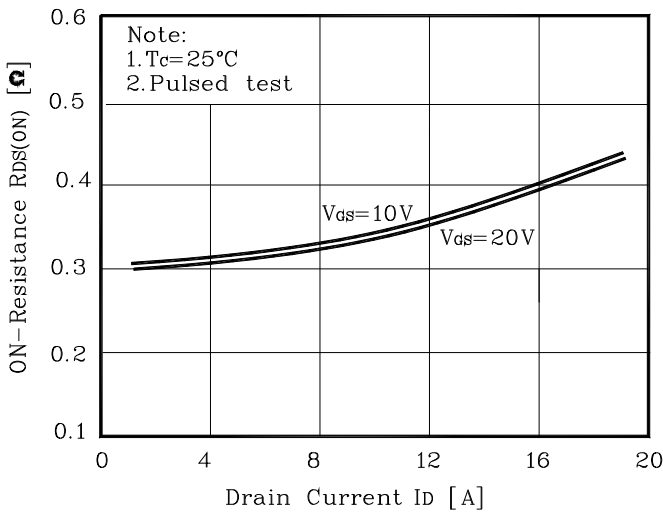


Fig. 4 $I_S - V_{SD}$

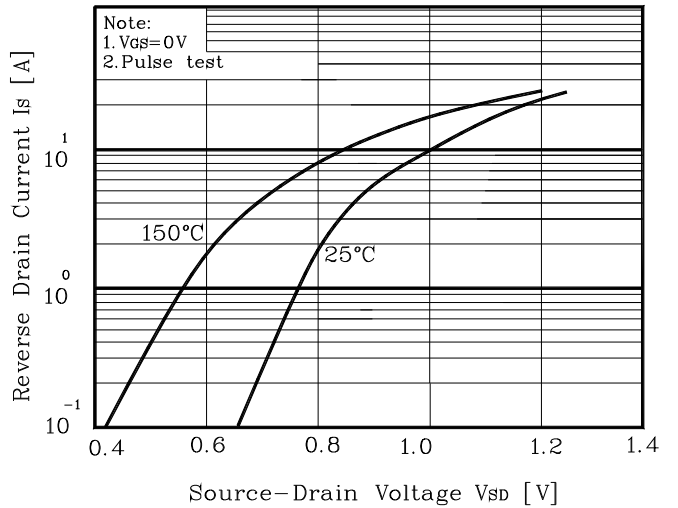


Fig. 5 Capacitance - V_{DS}

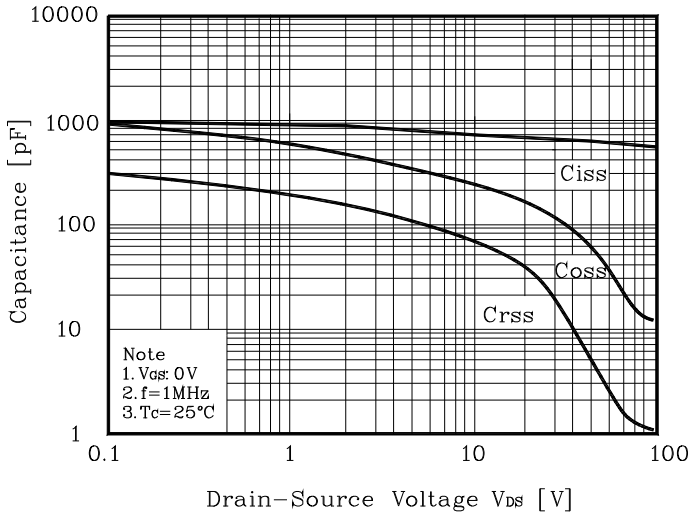
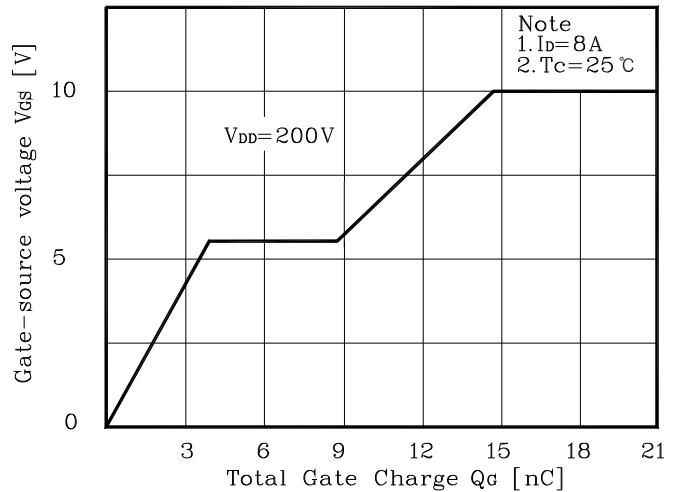


Fig. 6 $V_{GS} - Q_G$



Electrical Characteristic Curves (Continue)

Fig. 7 $V_{DSS} - T_J$

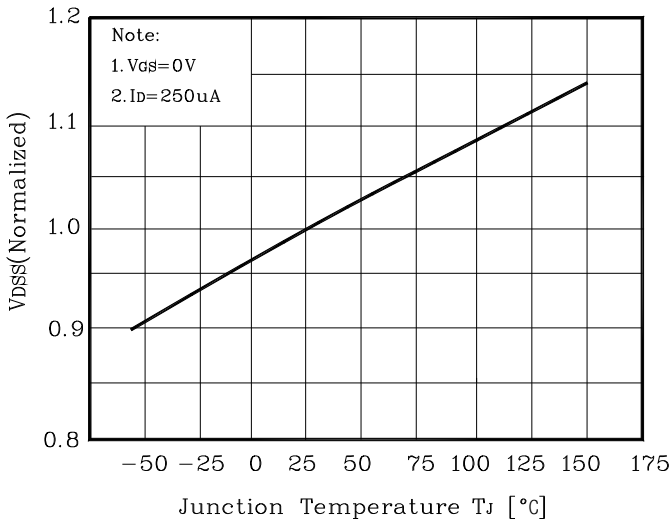


Fig. 8 $R_{DS(ON)} - T_J$

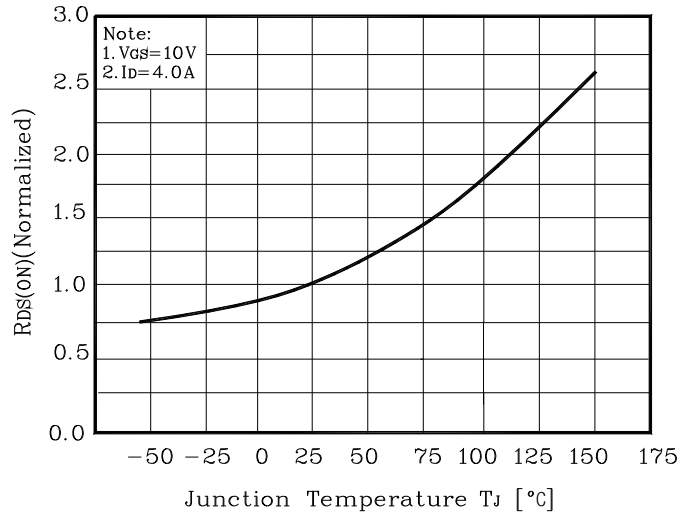


Fig. 9 $I_D - T_C$

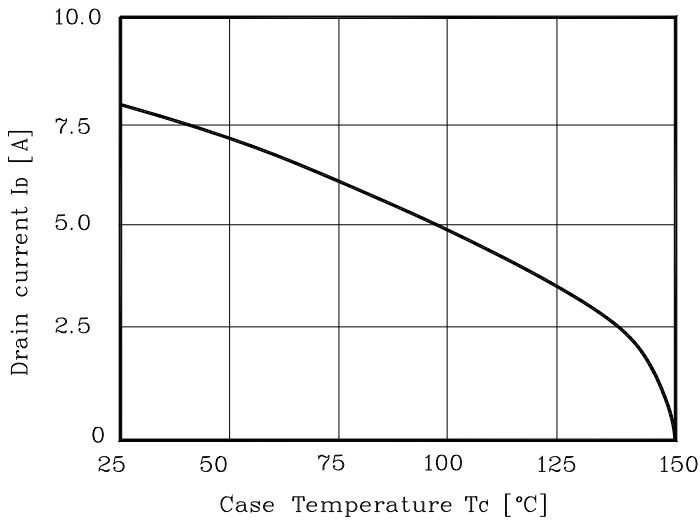


Fig. 10 Safe Operating Area

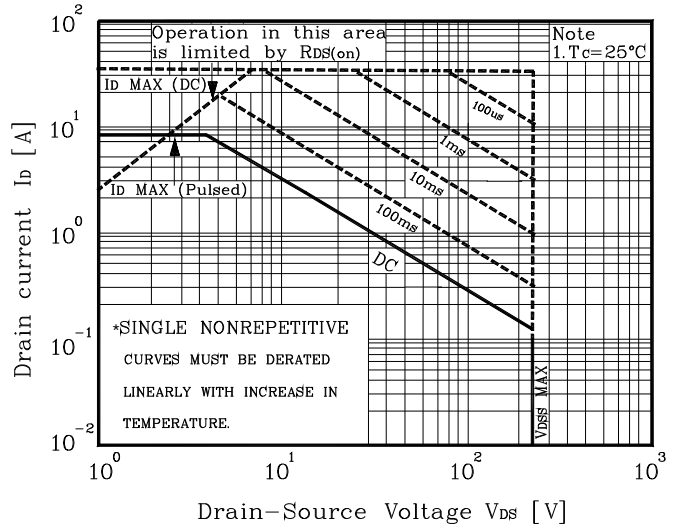


Fig. 11 Gate Charge Test Circuit & Waveform

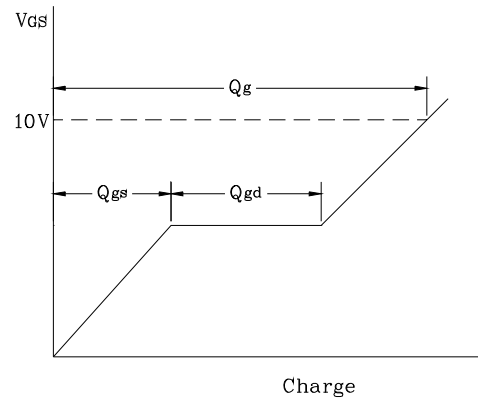
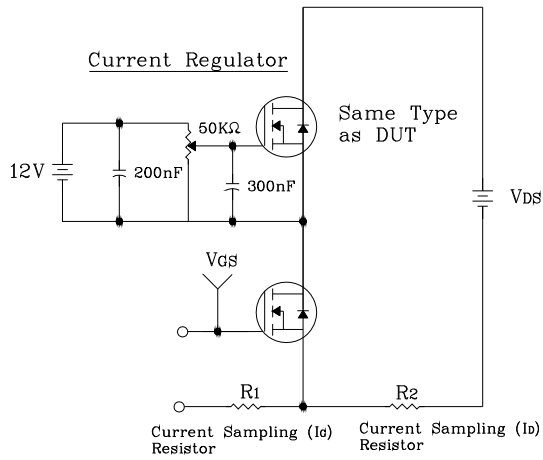


Fig. 12 Resistive Switching Test Circuit & Waveform

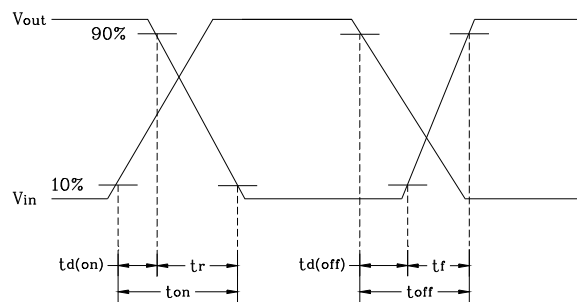
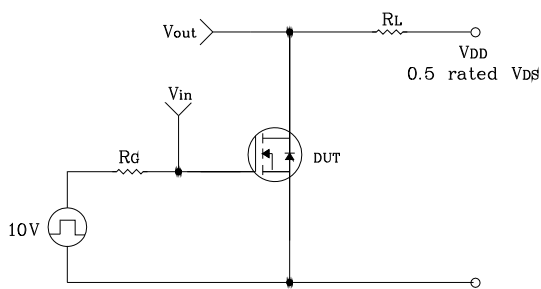


Fig. 13 E_{AS} Test Circuit & Waveform

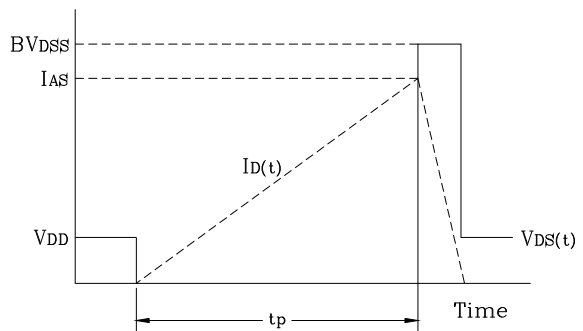
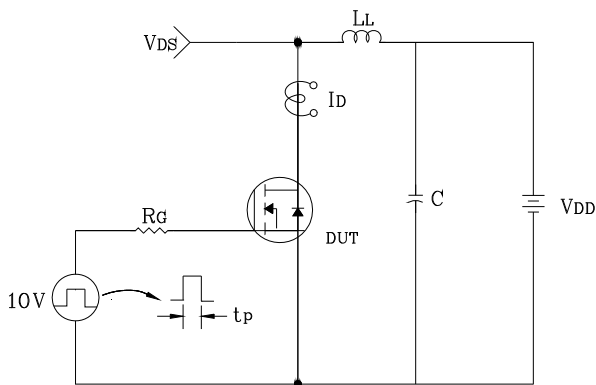
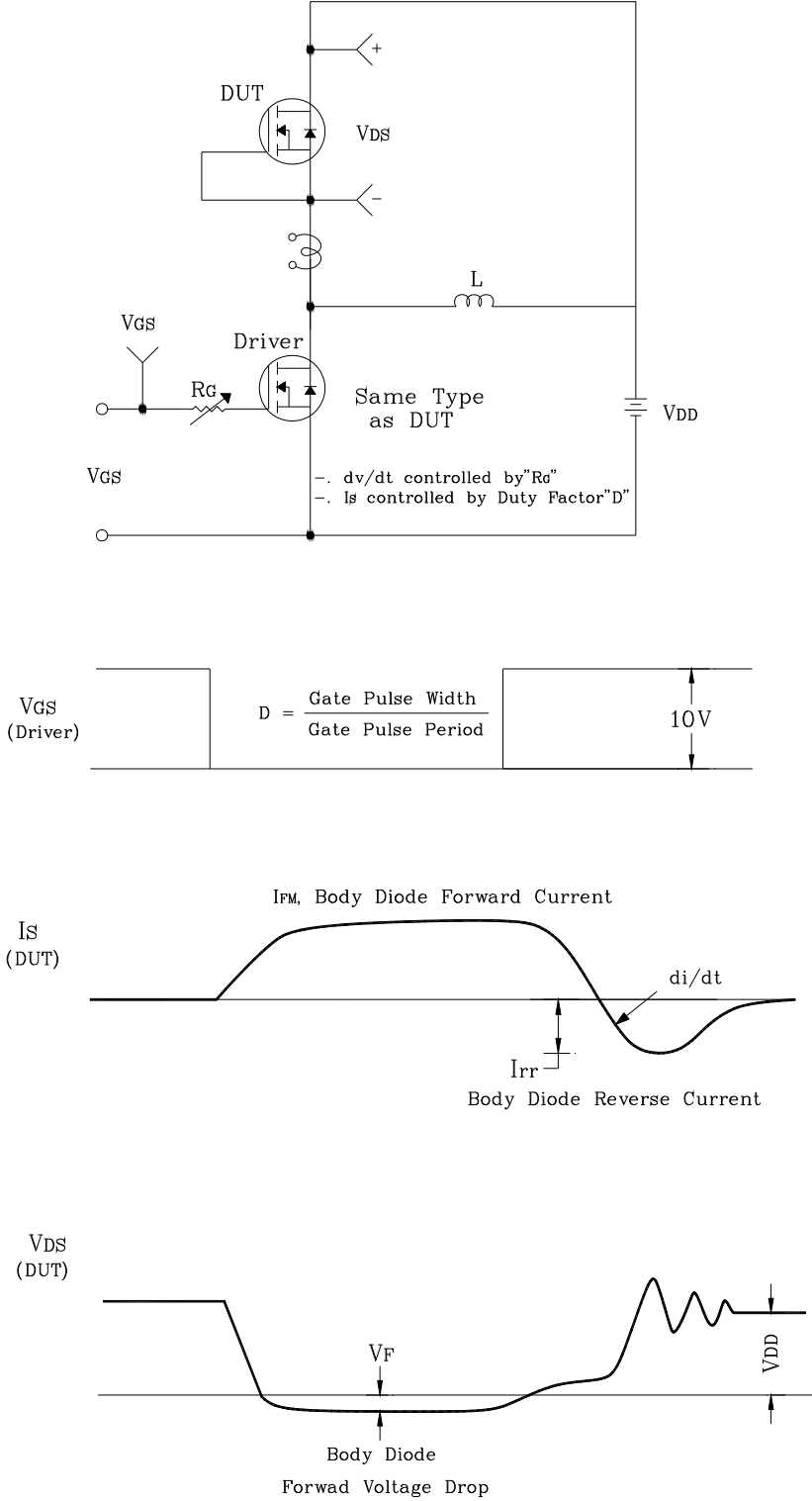
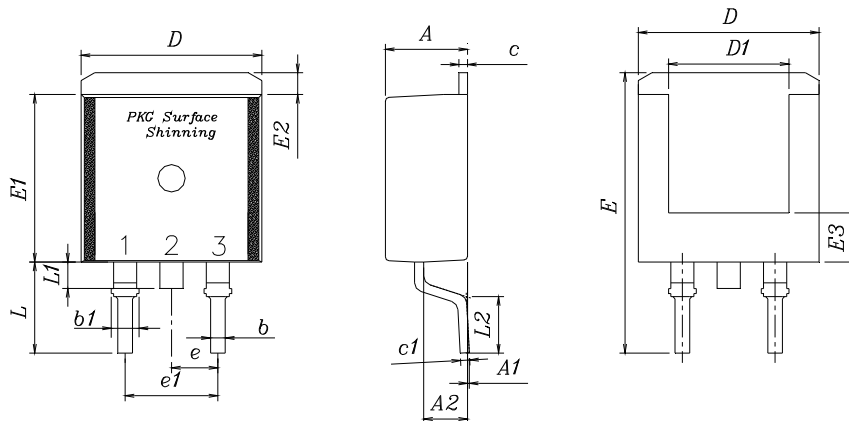


Fig. 14 Diode Reverse Recovery Time Test Circuit & Waveform

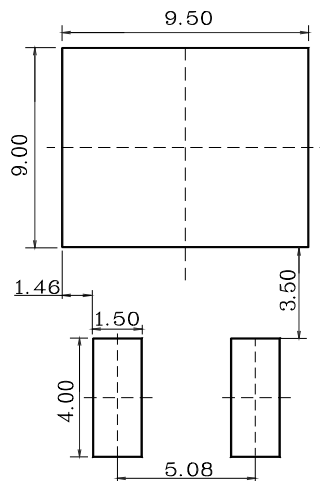


Package Outline Dimensions



SYMBOL	MILLIMETERS			NOTE
	MINIMUM	NOMINAL	MAXIMUM	
A	4.35	4.50	4.65	
A1	—	—	0.15	
A2	2.20	2.40	2.60	
b	0.70	0.80	0.90	
b1	1.17	1.27	1.37	
c	0.40	0.50	0.60	
c1	0.40	0.50	0.60	
D	9.80	10.00	10.20	
D1	6.40	6.60	6.80	
E	15.00	15.40	15.80	
E1	9.05	9.20	9.35	
E2	1.00	1.20	1.40	
E3	2.50	2.70	2.90	
e	2.34	2.54	2.74	
e1	4.88	5.08	5.28	
L	4.60	5.00	5.40	
L1	1.40	1.45	1.50	
L2	2.50	—	—	

※ Recommended Land Pattern [unit: mm]



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